

AMENDMENTS TO THE CLAIMS

Claim 1 (Canceled)

2. (Previously Amended) A substrate testing apparatus comprising:
- a first rail group made of a plurality of rails disposed in parallel with each other;
- a second rail group made of a plurality of rails disposed in parallel with each other in a direction that crosses said first rail group;
- a plurality of probe units disposed to cover respective intersections of the rails included in said first rail group and the rails included in said second rail group, all of said probe units being concurrently movable along the rails included in said first rail group and said second rail group;
- and
- corresponding interval maintaining means for keeping each rail included in said first rail group at an interval corresponding to an arrangement of locations to be measured on a substrate subjected to measurement,
- wherein said plurality of probe units each comprise a probing needle to be brought into contact with a surface of said substrate.

3. (Original) The substrate testing apparatus according to claim 2, wherein said corresponding interval maintaining means maintains the interval after changing the interval every time the arrangement of the locations to be measured changes.

4. (Original) The substrate testing apparatus according to claim 2, wherein said corresponding interval maintaining means comprises equal interval maintaining means for keeping each rail included in said first rail group at an equal interval.

5. (Currently Amended) ~~The substrate testing apparatus according to claim 4,~~  
~~further comprising:~~ A substrate testing apparatus comprising:

a first rail group made of a plurality of rails disposed in parallel with each other;

a second rail group made of a plurality of rails disposed in parallel with each other in a direction that crosses said first rail group;

a plurality of probe units disposed to cover respective intersections of the rails included in said first rail group and the rails included in said second rail group, all of said probe units being concurrently movable along the rails included in said first rail group and said second rail group, wherein said plurality of probe units each comprise a probing needle to be brought into contact with a surface of said substrate;

corresponding interval maintaining means for keeping each rail included in said first rail group at an interval corresponding to an arrangement of locations to be measured on a substrate subjected to measurement,

displacement measuring means for measuring a displacement of one or more observation points on the substrate subjected to measurement; and

displacement measurement value feedback means for setting the interval of each rail included in said first rail group, as defined by said equal interval maintaining means, in accordance with a displacement measurement value given by said displacement measuring means,

wherein said corresponding interval maintaining means comprises equal interval maintaining means for keeping each rail included in said first rail group at an equal interval.

6. (Currently Amended) ~~The substrate testing apparatus according to claim 4, further comprising:~~ A substrate testing apparatus comprising:

a first rail group made of a plurality of rails disposed in parallel with each other;

a second rail group made of a plurality of rails disposed in parallel with each other in a direction that crosses said first rail group;

a plurality of probe units disposed to cover respective intersections of the rails included in said first rail group and the rails included in said second rail group, all of said probe units being concurrently movable along the rails included in said first rail group and said second rail group, wherein said plurality of probe units each comprise a probing needle to be brought into contact with a surface of said substrate;

corresponding interval maintaining means for keeping each rail included in said first rail group at an interval corresponding to an arrangement of locations to be measured on a substrate subjected to measurement,

temperature measuring means for measuring a temperature; and

temperature measurement value feedback means for setting the interval of each rail included in said first rail group, as defined by said equal interval maintaining means, in accordance with a temperature measurement value given by said temperature measuring means,

wherein said corresponding interval maintaining means comprises equal interval maintaining means for keeping each rail included in said first rail group at an equal interval.

7. (Previously Amended) A substrate testing method using a plurality of probe units disposed to cover respective intersections of rails included in a first rail group made of a plurality of rails disposed in parallel with each other and rails included in a second rail group made of a plurality of rails disposed in parallel with each other in a direction that crosses said first rail group, said plurality of probe units being movable along the rails included in said first rail group and said second rail group and each comprising a probing needle to be brought into contact with a surface of a substrate subjected to measurement, wherein said probing needles are brought into contact with said substrate in a state in which an arrangement of said plurality of probe units is concurrently adjusted so that an interval between said probing needles corresponds to an arrangement of locations to be measured on said substrate.